

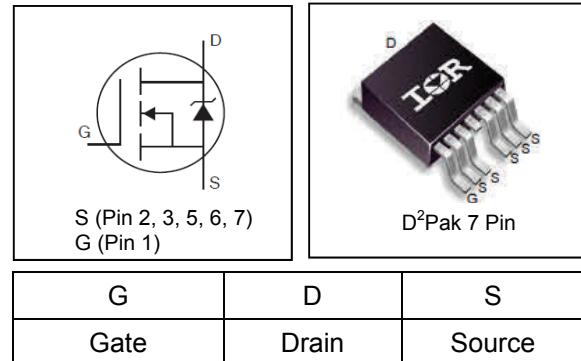
**Features**

- Advanced Process Technology
- Ultra Low On-Resistance
- 175°C Operating Temperature
- Fast Switching
- Repetitive Avalanche Allowed up to  $T_{jmax}$
- Lead-Free, RoHS Compliant
- Automotive Qualified \*

$V_{DSS}$	24V
$R_{DS(on)}$ typ.	0.8mΩ
	1.0mΩ
$I_D$ (Silicon Limited)	429A①
$I_D$ (Package Limited)	240A

**Description**

Specifically designed for Automotive applications, this HEXFET® Power MOSFET utilizes the latest processing techniques to achieve extremely low on-resistance per silicon area. Additional features of this design are a 175°C junction operating temperature, fast switching speed and improved repetitive avalanche rating. These features combine to make this design an extremely efficient and reliable device for use in Automotive applications and wide variety of other applications.



Base Part Number	Package Type	Standard Pack		Orderable Part Number
		Form	Quantity	
AUIRF1324S-7P	D²Pak 7 Pin	Tube	50	AUIRF1324S-7P

**Absolute Maximum Ratings**

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only; and functional operation of the device at these or any other condition beyond those indicated in the specifications is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability. The thermal resistance and power dissipation ratings are measured under board mounted and still air conditions. Ambient temperature (TA) is 25°C, unless otherwise specified.

Symbol	Parameter	Max.	Units
$I_D$ @ $T_C = 25^\circ\text{C}$	Continuous Drain Current, $V_{GS}$ @ 10V (Silicon Limited)	429①	A
$I_D$ @ $T_C = 100^\circ\text{C}$	Continuous Drain Current, $V_{GS}$ @ 10V (Silicon Limited)	303①	
$I_D$ @ $T_C = 25^\circ\text{C}$	Continuous Drain Current, $V_{GS}$ @ 10V (Package Limited)	240	
$I_{DM}$	Pulsed Drain Current ②	1640	
$P_D$ @ $T_C = 25^\circ\text{C}$	Maximum Power Dissipation	300	W
	Linear Derating Factor	2.0	W/°C
$V_{GS}$	Gate-to-Source Voltage	± 20	V
$E_{AS}$	Single Pulse Avalanche Energy (Thermally Limited) ③	230	mJ
$I_{AR}$	Avalanche Current ②	See Fig.14, 15, 18a, 18b	A
$E_{AR}$	Repetitive Avalanche Energy		mJ
$dv/dt$	Peak Diode Recovery ④	1.6	V/ns
$T_J$	Operating Junction and	-55 to + 175	°C
$T_{STG}$	Storage Temperature Range		
	Soldering Temperature, for 10 seconds (1.6mm from case)		

**Thermal Resistance**

Symbol	Parameter	Typ.	Max.	Units
$R_{\theta JC}$	Junction-to-Case ⑨	—	0.50	°C/W
$R_{\theta JA}$	Junction-to-Ambient ⑩	—	40	

HEXFET® is a registered trademark of Infineon.

\*Qualification standards can be found at [www.infineon.com](http://www.infineon.com)

**Static @  $T_J = 25^\circ\text{C}$  (unless otherwise specified)**

	Parameter	Min.	Typ.	Max.	Units	Conditions
$V_{(\text{BR})\text{DSS}}$	Drain-to-Source Breakdown Voltage	24	—	—	V	$V_{GS} = 0\text{V}$ , $I_D = 250\mu\text{A}$
$\Delta V_{(\text{BR})\text{DSS}}/\Delta T_J$	Breakdown Voltage Temp. Coefficient	—	0.023	—	V/ $^\circ\text{C}$	Reference to $25^\circ\text{C}$ , $I_D = 5\text{mA}$ ⑤
$R_{\text{DS}(\text{on})}$	Static Drain-to-Source On-Resistance	—	0.80	1.0	$\text{m}\Omega$	$V_{GS} = 10\text{V}$ , $I_D = 160\text{A}$ ⑤
$V_{GS(\text{th})}$	Gate Threshold Voltage	2.0	—	4.0	V	$V_{DS} = V_{GS}$ , $I_D = 250\mu\text{A}$
$g_{\text{fs}}$	Forward Trans conductance	190	—	—	S	$V_{DS} = 15\text{V}$ , $I_D = 160\text{A}$
$R_G$	Gate Resistance	—	3.0	—	$\Omega$	
$I_{\text{DSS}}$	Drain-to-Source Leakage Current	—	—	20	$\mu\text{A}$	$V_{DS} = 24\text{V}$ , $V_{GS} = 0\text{V}$
		—	—	250		$V_{DS} = 19\text{V}$ , $V_{GS} = 0\text{V}$ , $T_J = 125^\circ\text{C}$
$I_{\text{GSS}}$	Gate-to-Source Forward Leakage	—	—	200	nA	$V_{GS} = 20\text{V}$
	Gate-to-Source Reverse Leakage	—	—	-200		$V_{GS} = -20\text{V}$

**Dynamic Electrical Characteristics @  $T_J = 25^\circ\text{C}$  (unless otherwise specified)**

$Q_g$	Total Gate Charge	—	180	252	nC	$I_D = 75\text{A}$ $V_{DS} = 12\text{V}$ $V_{GS} = 10\text{V}$ ⑤
$Q_{gs}$	Gate-to-Source Charge	—	47	—		
$Q_{gd}$	Gate-to-Drain Charge	—	58	—		
$Q_{\text{sync}}$	Total Gate Charge Sync. ( $Q_g - Q_{gd}$ )	—	122	—		
$t_{d(\text{on})}$	Turn-On Delay Time	—	19	—	ns	$V_{DD} = 16\text{V}$ $I_D = 160\text{A}$ $R_G = 2.7\Omega$ $V_{GS} = 10\text{V}$ ⑤
$t_r$	Rise Time	—	240	—		
$t_{d(\text{off})}$	Turn-Off Delay Time	—	86	—		
$t_f$	Fall Time	—	93	—		
$C_{iss}$	Input Capacitance	—	7700	—	pF	$V_{GS} = 0\text{V}$ $V_{DS} = 19\text{V}$
$C_{oss}$	Output Capacitance	—	3380	—		
$C_{rss}$	Reverse Transfer Capacitance	—	1930	—		$f = 1.0\text{MHz}$ , See Fig. 5
$C_{oss \text{ eff. (ER)}}$	Effective Output Capacitance (Energy Related)	—	4780	—		$V_{GS} = 0\text{V}$ , $V_{DS} = 0\text{V}$ to $19\text{V}$ ⑦
$C_{oss \text{ eff. (TR)}}$	Effective Output Capacitance (Time Related)	—	4970	—		$V_{GS} = 0\text{V}$ , $V_{DS} = 0\text{V}$ to $19\text{V}$ ⑥

**Diode Characteristics**

	Parameter	Min.	Typ.	Max.	Units	Conditions
$I_s$	Continuous Source Current (Body Diode)	—	—	429 ①	A	MOSFET symbol showing the integral reverse p-n junction diode.
$I_{sM}$	Pulsed Source Current (Body Diode) ②	—	—	1640		
$V_{SD}$	Diode Forward Voltage	—	—	1.3	V	$T_J = 25^\circ\text{C}$ , $I_s = 160\text{A}$ , $V_{GS} = 0\text{V}$ ⑤
$t_{rr}$	Reverse Recovery Time	—	71	107	ns	$T_J = 25^\circ\text{C}$ $V_{DD} = 20\text{V}$
		—	74	110		$T_J = 125^\circ\text{C}$ $I_F = 160\text{A}$ ,
$Q_{rr}$	Reverse Recovery Charge	—	83	120	nC	$T_J = 25^\circ\text{C}$ $di/dt = 100\text{A}/\mu\text{s}$ ⑤
		—	92	140		$T_J = 125^\circ\text{C}$
$I_{RRM}$	Reverse Recovery Current	—	2.0	—	A	$T_J = 25^\circ\text{C}$
$t_{on}$	Forward Turn-On Time	Intrinsic turn-on time is negligible (turn-on is dominated by $L_s + L_D$ )				

**Notes:**

- ① Calculated continuous current based on maximum allowable junction temperature. Bond wire current limit is 240A. Note that current limitations arising from heating of the device leads may occur with some lead mounting arrangements.
- ② Repetitive rating; pulse width limited by max. junction temperature.
- ③ Limited by  $T_{J\text{max}}$ , starting  $T_J = 25^\circ\text{C}$ ,  $L = 0.018\text{mH}$ ,  $R_G = 25\Omega$ ,  $I_{AS} = 160\text{A}$ ,  $V_{GS} = 10\text{V}$ . Part not recommended for use above this value.
- ④  $I_{SD} \leq 160\text{A}$ ,  $di/dt \leq 600\text{A}/\mu\text{s}$ ,  $V_{DD} \leq V_{(\text{BR})\text{DSS}}$ ,  $T_J \leq 175^\circ\text{C}$ .
- ⑤ Pulse width  $\leq 400\mu\text{s}$ ; duty cycle  $\leq 2\%$ .
- ⑥  $C_{oss \text{ eff. (TR)}}$  is a fixed capacitance that gives the same charging time as  $C_{oss}$  while  $V_{DS}$  is rising from 0 to 80%  $V_{DSS}$ .
- ⑦  $C_{oss \text{ eff. (ER)}}$  is a fixed capacitance that gives the same energy as  $C_{oss}$  while  $V_{DS}$  is rising from 0 to 80%  $V_{DSS}$ .
- ⑧ When mounted on 1" square PCB (FR-4 or G-10 Material). For recommended footprint and soldering techniques refer to application note #AN-994
- ⑨  $R_\theta$  is measured at  $T_J$  approximately  $90^\circ\text{C}$ .

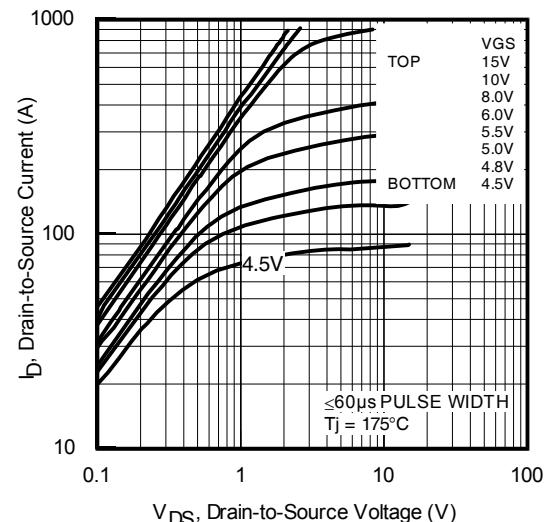
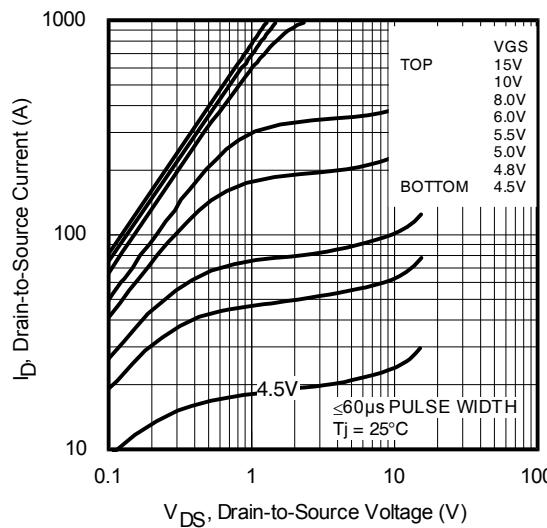
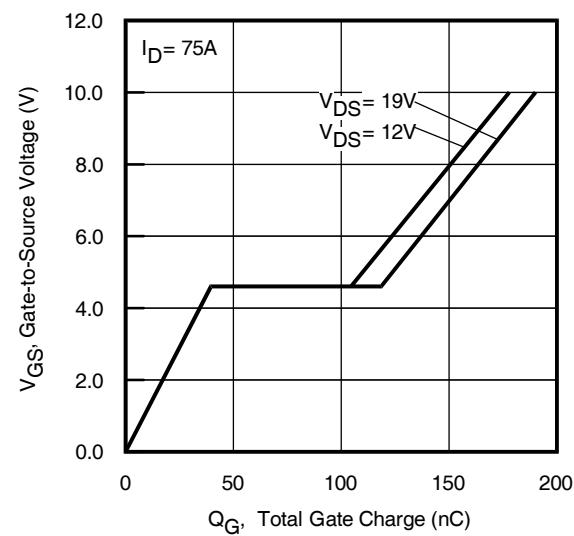
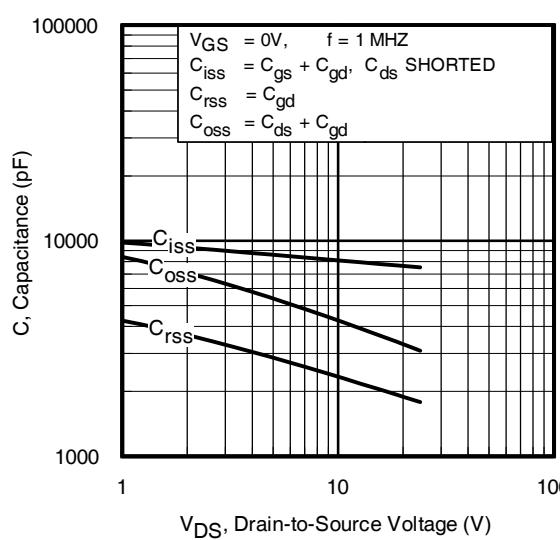
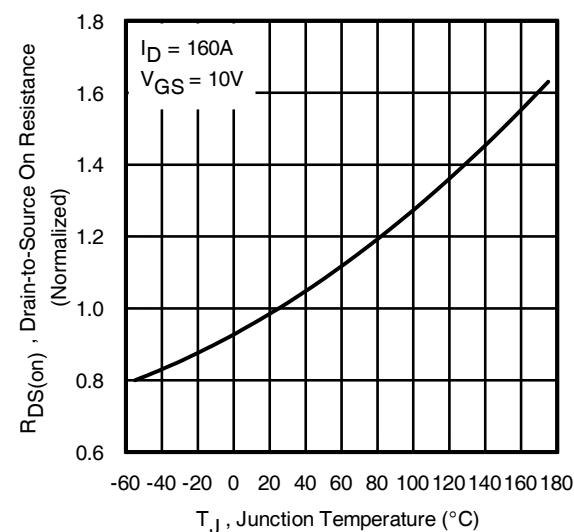
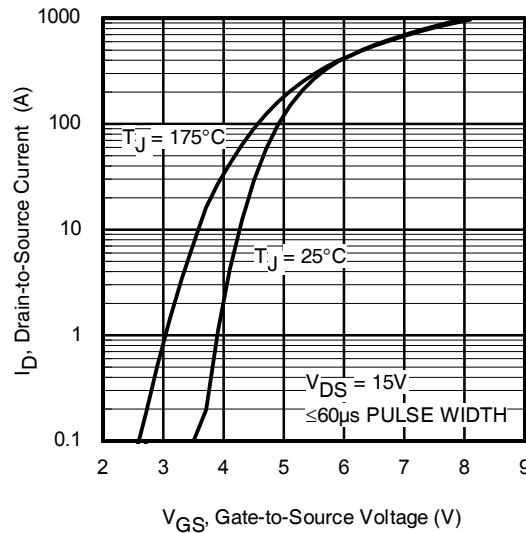
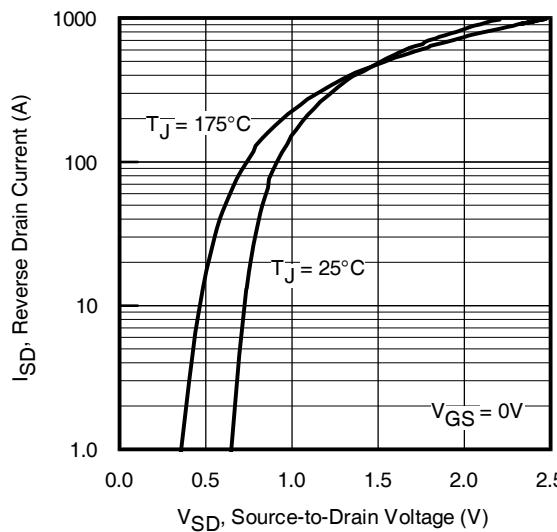
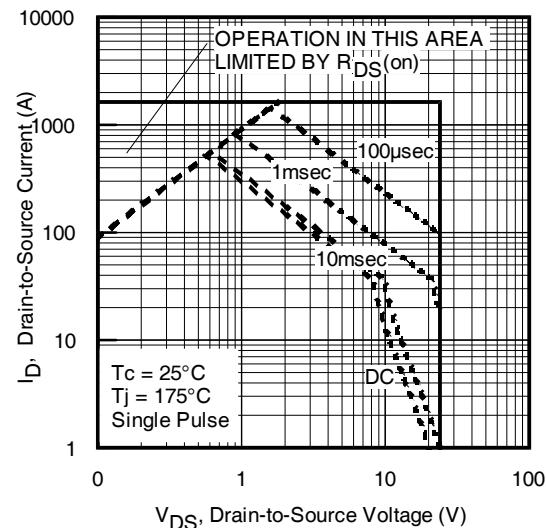


Fig. 1 Typical Output Characteristics

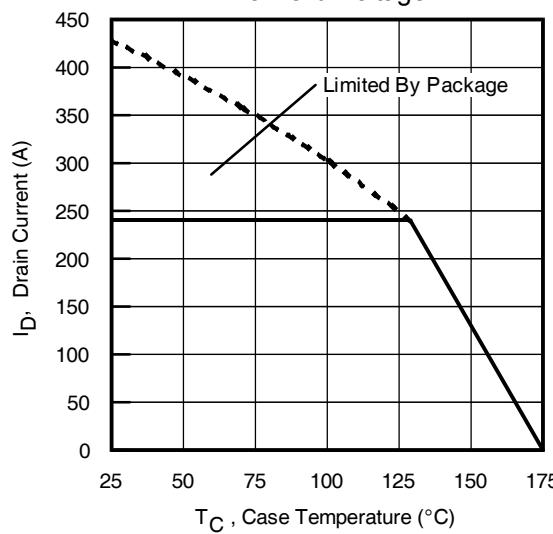




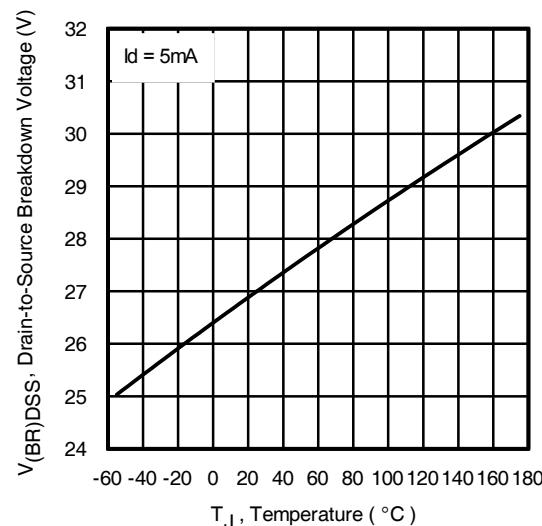
**Fig. 7** Typical Source-to-Drain Diode Forward Voltage



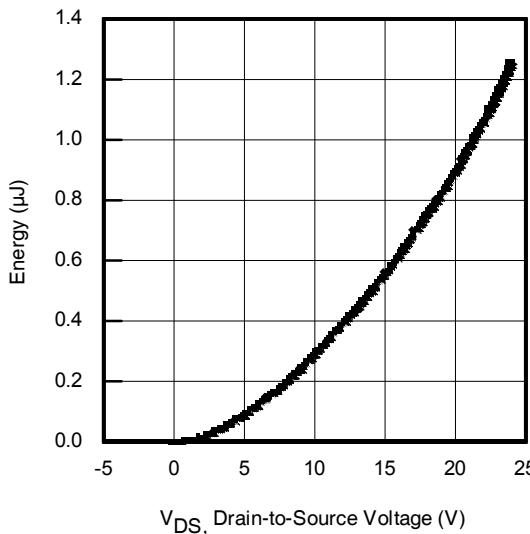
**Fig 8.** Maximum Safe Operating Area



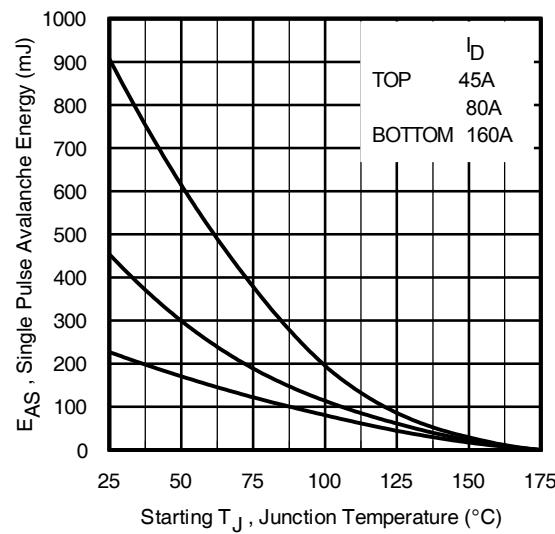
**Fig 9.** Maximum Drain Current vs. Case Temperature



**Fig 10.** Drain-to-Source Breakdown Voltage



**Fig 11.** Typical Coss Stored Energy



**Fig 12.** Maximum Avalanche Energy vs. Drain Current

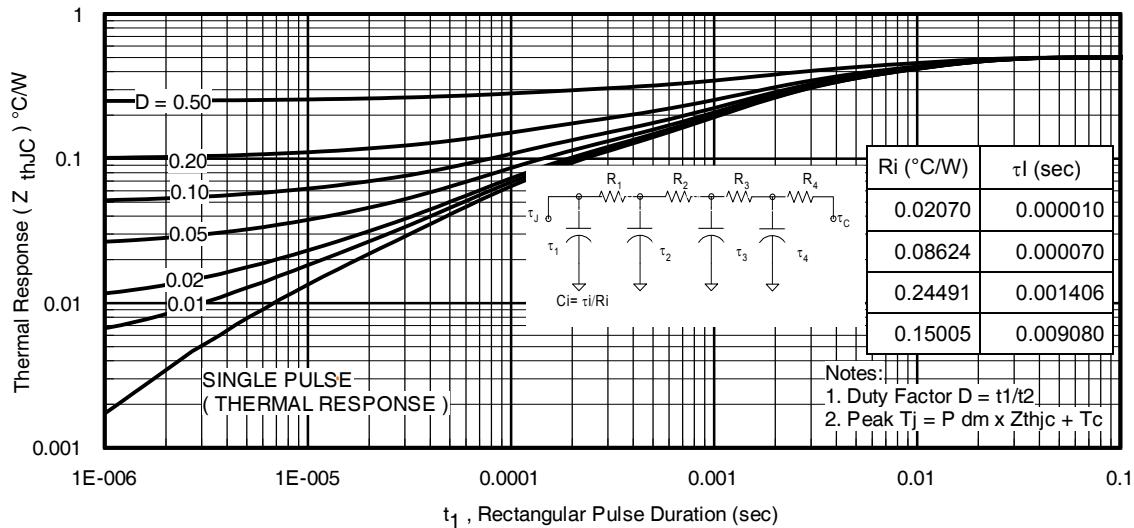


Fig 13. Maximum Effective Transient Thermal Impedance, Junction-to-Case

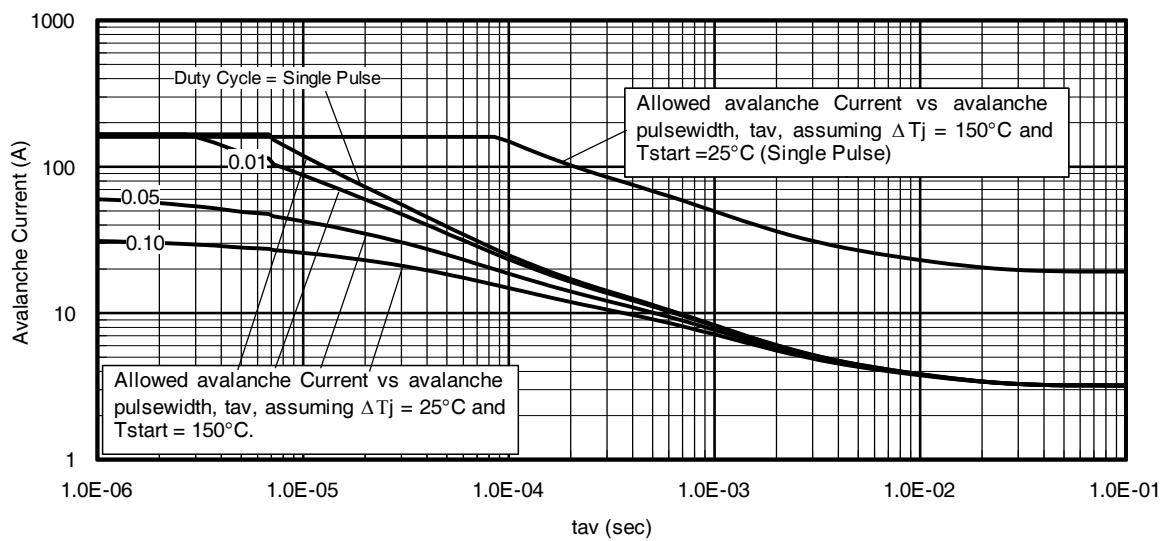
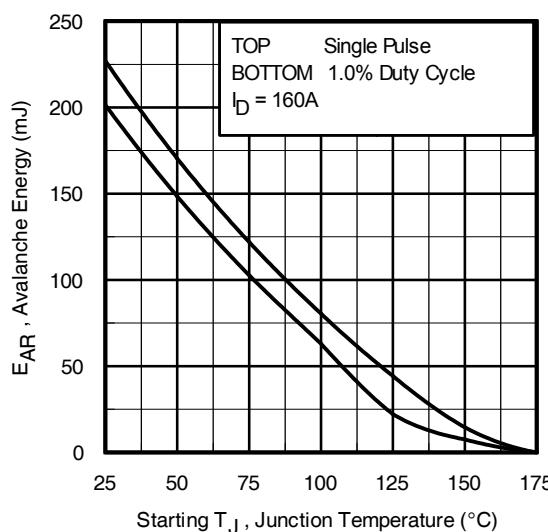


Fig 14. Avalanche Current vs. Pulse width



**Fig 15.** Maximum Avalanche Energy vs. Temperature

**Notes on Repetitive Avalanche Curves , Figures 14, 15:**

(For further info, see AN-1005 at [www.infineon.com](http://www.infineon.com))

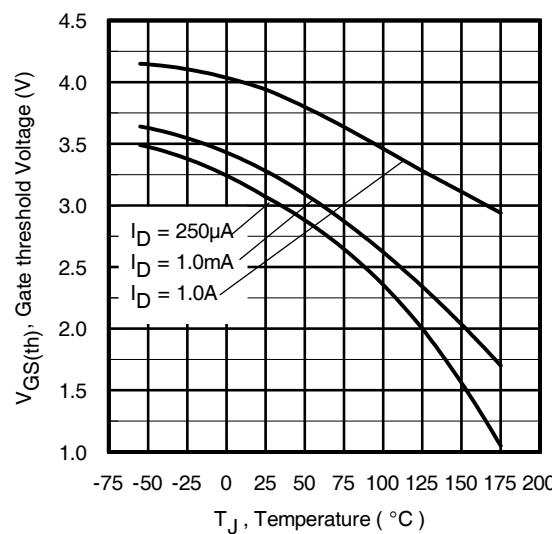
1. Avalanche failures assumption:  
Purely a thermal phenomenon and failure occurs at a temperature far in excess of  $T_{jmax}$ . This is validated for every part type.
2. Safe operation in Avalanche is allowed as long as  $T_{jmax}$  is not exceeded.
3. Equation below based on circuit and waveforms shown in Figures 18a, 18b.
4.  $P_{D(ave)}$  = Average power dissipation per single avalanche pulse.
5.  $BV$  = Rated breakdown voltage (1.3 factor accounts for voltage increase during avalanche).
6.  $I_{av}$  = Allowable avalanche current.
7.  $\Delta T$  = Allowable rise in junction temperature, not to exceed  $T_{jmax}$  (assumed as 25°C in Figure 13, 14).

$t_{av}$  = Average time in avalanche.  
 $D$  = Duty cycle in avalanche =  $t_{av} \cdot f$   
 $Z_{thJC}(D, t_{av})$  = Transient thermal resistance, see Figures 13)

$$P_{D(ave)} = 1/2 (1.3 \cdot BV \cdot I_{av}) = \Delta T / Z_{thJC}$$

$$I_{av} = 2\Delta T / [1.3 \cdot BV \cdot Z_{th}]$$

$$E_{AS(AR)} = P_{D(ave)} \cdot t_{av}$$



**Fig 16.** Threshold Voltage vs. Temperature

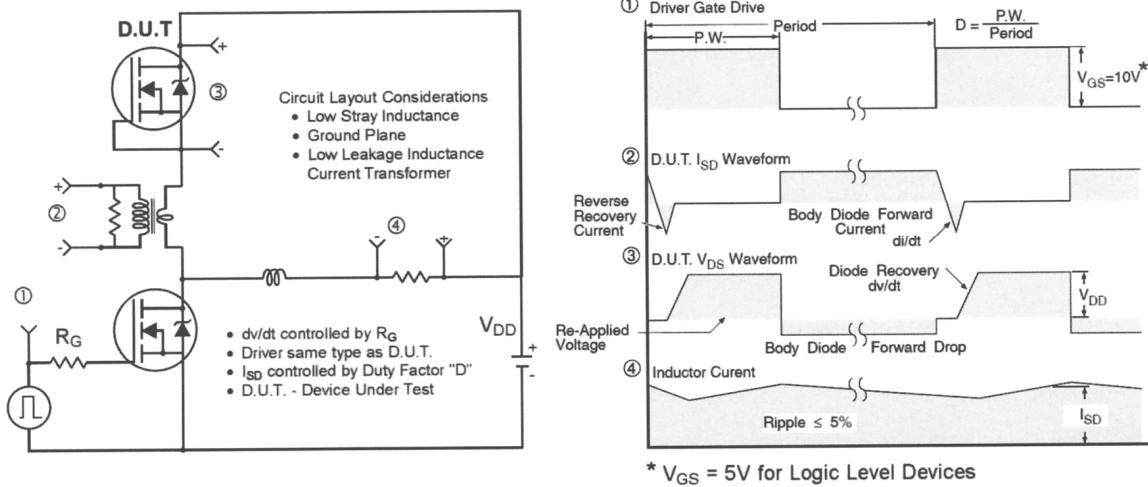


Fig 17. Peak Diode Recovery  $dv/dt$  Test Circuit for N-Channel HEXFET® Power MOSFETs

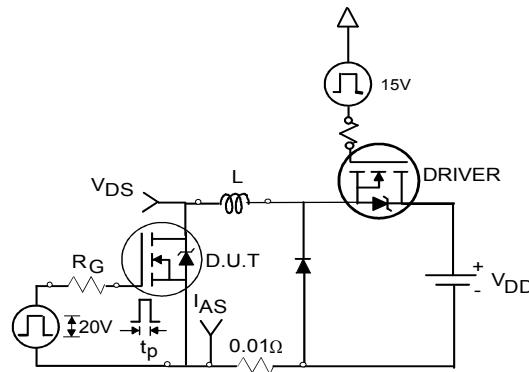


Fig 18a. Unclamped Inductive Test Circuit

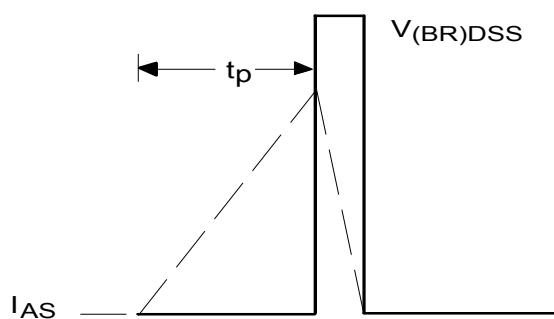


Fig 18b. Unclamped Inductive Waveforms

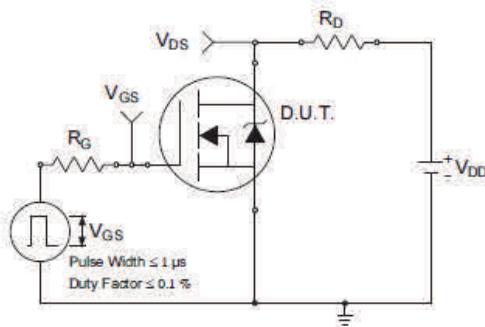


Fig 19a. Switching Time Test Circuit

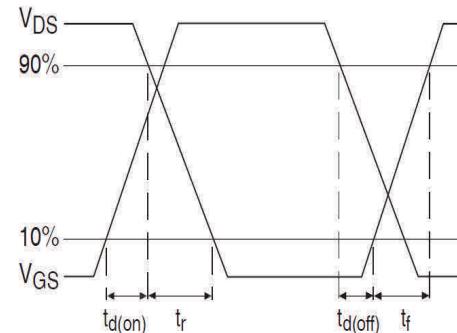


Fig 19b. Switching Time Waveforms

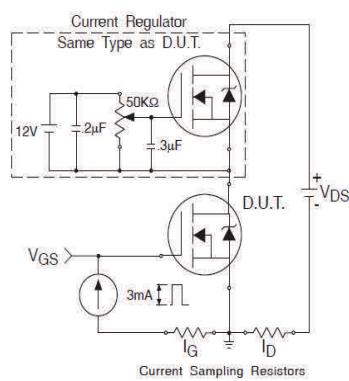


Fig 20a. Gate Charge Test Circuit

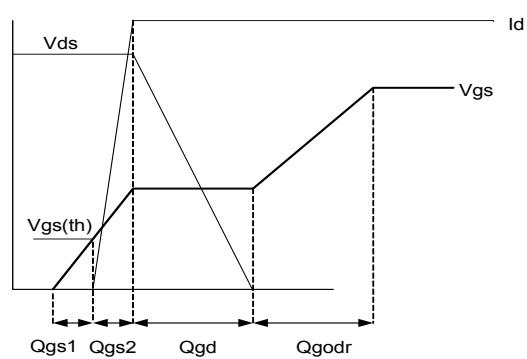
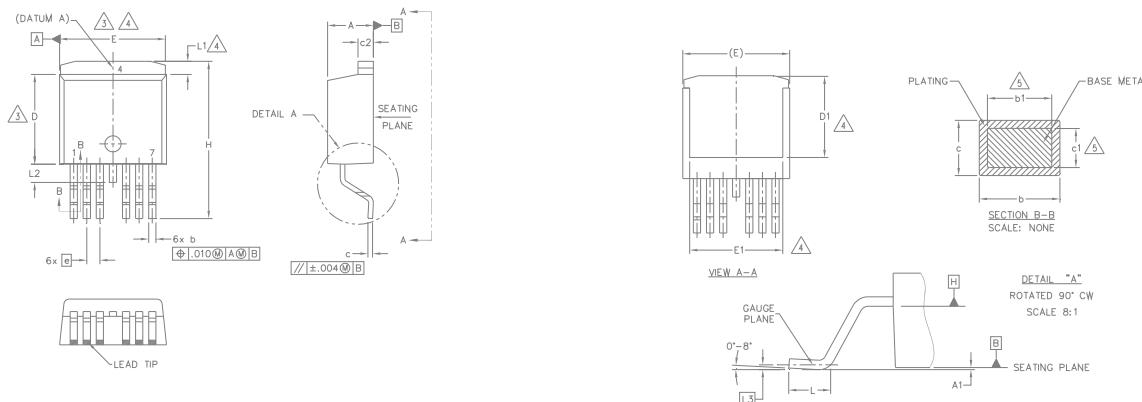


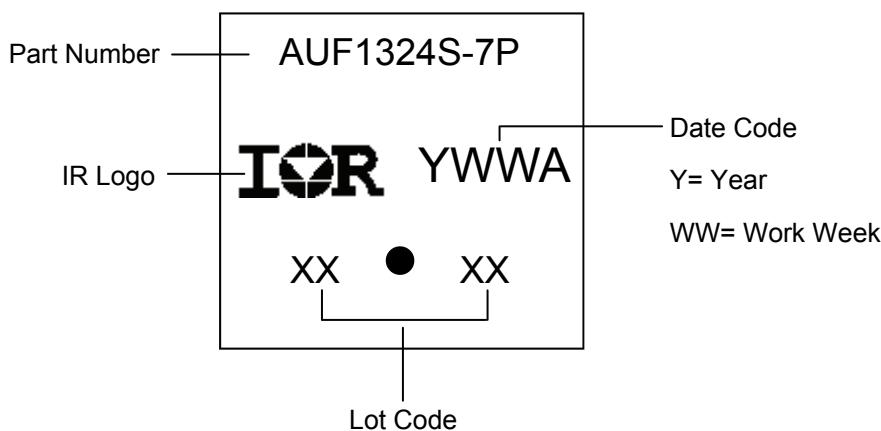
Fig 20b. Gate Charge Waveform

**D<sup>2</sup>Pak - 7 Pin Package Outline (Dimensions are shown in millimeters (inches))**


S Y M B O L	DIMENSIONS				N O T E S	
	MILLIMETERS		INCHES			
	MIN.	MAX.	MIN.	MAX.		
A	4.06	4.83	.160	.190		
A1	—	0.254	—	.010		
b	0.51	0.99	.020	.036	5	
b1	0.51	0.89	.020	.032		
c	0.38	0.74	.015	.029		
c1	0.38	0.58	.015	.023		
c2	1.14	1.65	.045	.065		
D	8.38	9.65	.330	.380	3	
D1	6.86	7.42	.270	.292	4	
E	9.65	10.54	.380	.415	3,4	
E1	6.22	8.48	.245	.334	4	
e	1.27 BSC		.050 BSC			
H	14.61	15.88	.575	.625		
L	1.78	2.79	.070	.110		
L1	—	1.68	—	.066		
L2	—	1.78	—	.070		
L3	0.25 BSC		.010 BSC			

## NOTES:

1. DIMENSIONING AND TOLERANCING AS PER ASME Y14.5M-1994
2. DIMENSIONS ARE SHOWN IN MILLIMETERS [INCHES].
3. DIMENSION D & E DO NOT INCLUDE MOLD FLASH. MOLD FLASH SHALL NOT EXCEED 0.127 [.005"] PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTMOST EXTREMES OF THE PLASTIC BODY AT DATUM H.
4. THERMAL PAD CONTOUR OPTIONAL WITHIN DIMENSION E, L1, D1 & E1.
5. DIMENSION b1 AND c1 APPLY TO BASE METAL ONLY.
6. DATUM A & B TO BE DETERMINED AT DATUM PLANE H.
7. CONTROLLING DIMENSION: INCH.
8. OUTLINE CONFORMS TO JEDEC OUTLINE TO-263CB.  
EXCEPT FOR DIMS. E, E1 & D1.

**D<sup>2</sup>Pak - 7 Pin Part Marking Information**


## Qualification Information

<b>Qualification Level</b>		Automotive (per AEC-Q101)	
		Comments: This part number(s) passed Automotive qualification. Infineon's Industrial and Consumer qualification level is granted by extension of the higher Automotive level.	
<b>Moisture Sensitivity Level</b>		D <sup>2</sup> -Pak 7 Pin	MSL1
<b>ESD</b>	Machine Model	Class M4 <sup>†</sup> AEC-Q101-002	
	Human Body Model	Class H3A <sup>†</sup> AEC-Q101-001	
	Charged Device Model	Class C3 <sup>†</sup> AEC-Q101-005	
<b>RoHS Compliant</b>		Yes	

† Highest passing voltage.

## Revision History

Date	Comments
9/30/2015	<ul style="list-style-type: none"> <li>• Updated datasheet with corporate template</li> <li>• Corrected ordering table on page 1.</li> <li>• Updated typo on GFS on page 2.</li> </ul>

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